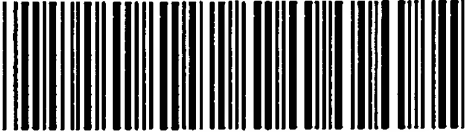


<div>Search Notes</div> <div></div>	Application No.	Applicant(s)	
	10/080,696	GOKER, TURGUY	
	Examiner	Art Unit	
	Toan M Le	2863	

SEARCHED			
Class	Subclass	Date	Examiner
702	179	4/14/2004	TL
700	51	4/15/2004	TL
700	108	4/15/2004	TL
703	2	4/15/2004	TL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
702	179	4/15/2004	TL
700	51	4/15/2004	TL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Statistical Process Control; Mean; Variance; Sum; Square; Sample; Loop; Code	10/8/2003	TL
Real-Time, Statistical, Computation, Variance, Mean, Standard Deviation, Process, Sample, Variable, Performance	4/14/2004	TL
Bias Corrected Variance	4/15/2004	TL
Embedded System	4/15/2004	TL
East, Web, and NPL Search		